

Highly sensitive detection of polarized light using a new IV-V group 2D orthorhombic SiP

Chunlong Li,^a Shanpeng Wang,^{*,a,b}, Chenning Li,^a Tongtong Yu,^a Ning Jia,^a Jie Qiao,^a Min Zhu,^a Duo Liu,^{a,b} and Xutang Tao^{*,a,b},

a. State Key Laboratory of Crystal Materials, Shandong University, Jinan, 250100, China.

b. Key Laboratory of Functional Crystal Materials and Device (Shandong University, Ministry of Education), Jinan, 250100, China.

Table S1. Calculated Γ -point Frequencies of o-SiP
Based on DFT

No.	PBE-GGA (cm^{-1})	Exp. (cm^{-1})	Raman mode
1	0	-	A ₁
2	15.0	-	A ₂
3	16.4	-	A ₁
4	98.6	106	A ₁
5	108.0	113	A ₂
6	116.6	-	A ₁
7	132.8	-	A ₁
8	139.9	132	A ₂
9	160.1	162	A ₁
10	161.8	140	A ₂
11	180.7	171	A ₁
12	220.9	188	A ₁
13	235.1	231	A ₁
14	248.9	-	A ₁
15	280.1	261	A ₁
16	297.8	305	A ₁
17	348.6	-	A ₁

18	379.0	-	A ₁
19	390.9	-	A ₁
20	429.3	-	A ₂
21	442.8	-	A ₁
22	445.0	-	A ₂
23	449.4	443	A ₂
24	455.2	-	A ₁
25	472.0	-	A ₁
26	476.1	-	A ₁
27	484.3	-	A ₁
28	488.1	-	A ₁
29	496.3	491	A ₁
30	523.2	516	A ₁
31	537.4	553	A ₁

“-” represents the calculated peaks can not be detected in experiments.